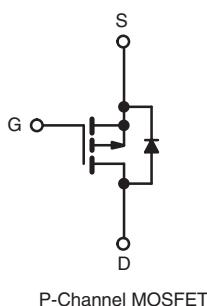


## Power MOSFET

PRODUCT SUMMARY		
$V_{DS}$ (V)	-	100
$R_{DS(on)}$ ( $\Omega$ )	$V_{GS} = -10\text{ V}$	0.60
$Q_g$ (Max.) (nC)	-	18
$Q_{gs}$ (nC)	-	3.0
$Q_{gd}$ (nC)	-	9.0
Configuration	-	Single



### ORDERING INFORMATION

Package	SMD-220	SMD-220	SMD-220
Lead (Pb)-free	IRF9520SPbF SiHF9520S-E3	IRF9520STRLPbFa SiHF9520STL-E3a	IRF9520STRRPbFa SiHF9520STR-E3a
SnPb	IRF9520S SiHF9520S	IRF9520STRLa SiHF9520STLa	- -

#### Note

a. See device orientation.

### ABSOLUTE MAXIMUM RATINGS $T_C = 25\text{ }^\circ\text{C}$ , unless otherwise noted

PARAMETER	SYMBOL	LIMIT	UNIT
Drain-Source Voltage	$V_{DS}$	- 100	
Gate-Source Voltage	$V_{GS}$	$\pm 20$	
Continuous Drain Current	$I_D$	- 6.8 - 4.8	A
Pulsed Drain Current <sup>a</sup>	$I_{DM}$	- 27	
Linear Derating Factor		0.40	
Linear Derating Factor (PCB Mount) <sup>e</sup>		0.025	$\text{W}/^\circ\text{C}$
Single Pulse Avalanche Energy <sup>b</sup>	$E_{AS}$	300	$\text{mJ}$
Avalanche Current <sup>a</sup>	$I_{AR}$	- 6.8	A
Repetitive Avalanche Energy <sup>a</sup>	$E_{AR}$	6.0	$\text{mJ}$
Maximum Power Dissipation	$P_D$	60	
Maximum Power Dissipation (PCB Mount) <sup>e</sup>		3.7	$\text{W}$
Peak Diode Recovery $dV/dt^c$	$dV/dt$	- 5.5	$\text{V}/\text{ns}$
Operating Junction and Storage Temperature Range	$T_J, T_{stg}$	- 55 to + 175	
Soldering Recommendations (Peak Temperature)	for 10 s	300 <sup>d</sup>	$^\circ\text{C}$

#### Notes

- a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).
- b.  $V_{DD} = -25\text{ V}$ , starting  $T_J = 25\text{ }^\circ\text{C}$ ,  $L = 9.7\text{ mH}$ ,  $R_G = 25\text{ }\Omega$ ,  $I_{AS} = -6.8\text{ A}$  (see fig. 12).
- c.  $I_{SD} \leq -6.8\text{ A}$ ,  $dI/dt \leq 110\text{ A}/\mu\text{s}$ ,  $V_{DD} \leq V_{DS}$ ,  $T_J \leq 175\text{ }^\circ\text{C}$ .
- d. 1.6 mm from case.
- e. When mounted on 1" square PCB (FR-4 or G-10 material).

\* Pb containing terminations are not RoHS compliant, exemptions may apply



RoHS  
COMPLIANT

**THERMAL RESISTANCE RATINGS**

PARAMETER	SYMBOL	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	$R_{thJA}$	-	62	$^{\circ}\text{C}/\text{W}$
Maximum Junction-to-Ambient (PCB Mount) <sup>a</sup>	$R_{thJA}$	-	40	
Maximum Junction-to-Case (Drain)	$R_{thJC}$	-	2.5	

**Note**

a. When mounted on 1" square PCB (FR-4 or G-10 material).

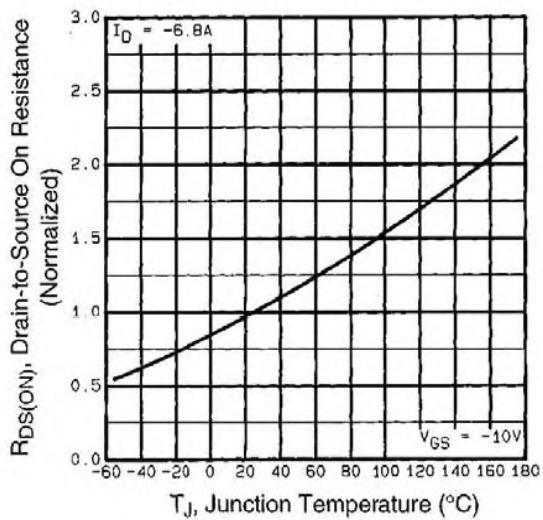
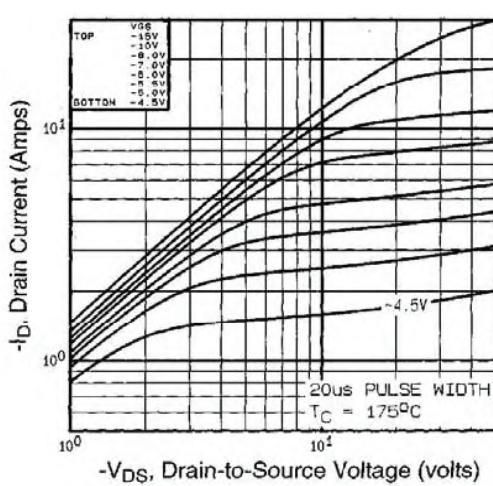
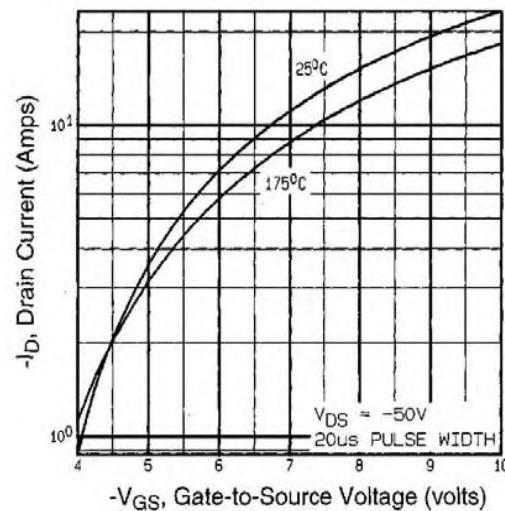
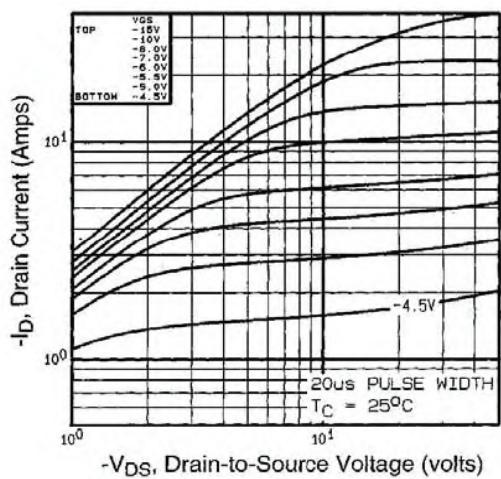
**SPECIFICATIONS**  $T_J = 25 \text{ }^{\circ}\text{C}$ , unless otherwise noted

PARAMETER	SYMBOL	TEST CONDITIONS		MIN.	TYP.	MAX.	UNIT	
<b>Static</b>								
Drain-Source Breakdown Voltage	$V_{DS}$	$V_{GS} = 0 \text{ V}$ , $I_D = - 250 \mu\text{A}$		- 100	-	-	V	
$V_{DS}$ Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to $25 \text{ }^{\circ}\text{C}$ , $I_D = - 1 \text{ mA}$		-	0.13	-	$\text{V}/^{\circ}\text{C}$	
Gate-Source Threshold Voltage	$V_{GS(th)}$	$V_{DS} = V_{GS}$ , $I_D = - 250 \mu\text{A}$		- 2.0	-	- 4.0	V	
Gate-Source Leakage	$I_{GSS}$	$V_{GS} = \pm 20 \text{ V}$		-	-	$\pm 100$	nA	
Zero Gate Voltage Drain Current	$I_{DSS}$	$V_{DS} = - 100 \text{ V}$ , $V_{GS} = 0 \text{ V}$		-	-	- 100	$\mu\text{A}$	
		$V_{DS} = - 80 \text{ V}$ , $V_{GS} = 0 \text{ V}$ , $T_J = 150 \text{ }^{\circ}\text{C}$		-	-	- 500		
Drain-Source On-State Resistance	$R_{DS(on)}$	$V_{GS} = - 10 \text{ V}$	$I_D = - 4.1 \text{ A}^b$	-	-	0.60	$\Omega$	
Forward Transconductance	$g_{fs}$	$V_{DS} = - 50 \text{ V}$ , $I_D = - 4.1 \text{ A}^b$		2.0	-	-	S	
<b>Dynamic</b>								
Input Capacitance	$C_{iss}$	$V_{GS} = 0 \text{ V}$ , $V_{DS} = - 25 \text{ V}$ , $f = 1.0 \text{ MHz}$ , see fig. 5		-	390	-	pF	
Output Capacitance	$C_{oss}$			-	170	-		
Reverse Transfer Capacitance	$C_{rss}$			-	45	-		
Total Gate Charge	$Q_g$	$V_{GS} = 10 \text{ V}$	$I_D = - 6.8 \text{ A}$ , $V_{DS} = - 80 \text{ V}$ , see fig. 6 and 13 <sup>b</sup>	-	-	18	nC	
Gate-Source Charge	$Q_{gs}$			-	-	3.0		
Gate-Drain Charge	$Q_{gd}$			-	-	9.0		
Turn-On Delay Time	$t_{d(on)}$	$V_{DD} = - 50 \text{ V}$ , $I_D = - 6.8 \text{ A}$ , $R_G = 18 \Omega$ , $R_D = 7.1 \Omega$ , see fig. 10 <sup>b</sup>		-	9.6	-	ns	
Rise Time	$t_r$			-	29	-		
Turn-Off Delay Time	$t_{d(off)}$			-	21	-		
Fall Time	$t_f$			-	25	-		
Internal Drain Inductance	$L_D$	Between lead, 6 mm (0.25") from package and center of die contact		-	4.5	-	nH	
Internal Source Inductance	$L_S$			-	7.5	-		
<b>Drain-Source Body Diode Characteristics</b>								
Continuous Source-Drain Diode Current	$I_S$	MOSFET symbol showing the integral reverse p - n junction diode		-	-	- 6.8	A	
Pulsed Diode Forward Current <sup>a</sup>	$I_{SM}$			-	-	- 27		
Body Diode Voltage	$V_{SD}$	$T_J = 25 \text{ }^{\circ}\text{C}$ , $I_S = - 6.8 \text{ A}$ , $V_{GS} = 0 \text{ V}^b$		-	-	- 6.3	V	
Body Diode Reverse Recovery Time	$t_{rr}$	$T_J = 25 \text{ }^{\circ}\text{C}$ , $I_F = - 6.8 \text{ A}$ , $dI/dt = 100 \text{ A}/\mu\text{s}^b$		-	98	200	ns	
Body Diode Reverse Recovery Charge	$Q_{rr}$			-	0.33	0.66	$\mu\text{C}$	
Forward Turn-On Time	$t_{on}$	Intrinsic turn-on time is negligible (turn-on is dominated by $L_S$ and $L_D$ )						

**Notes**

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11).

b. Pulse width  $\leq 300 \mu\text{s}$ ; duty cycle  $\leq 2 \%$ .

**TYPICAL CHARACTERISTICS** 25 °C, unless otherwise noted


# IRF9520S, SiHF9520S

Vishay Siliconix

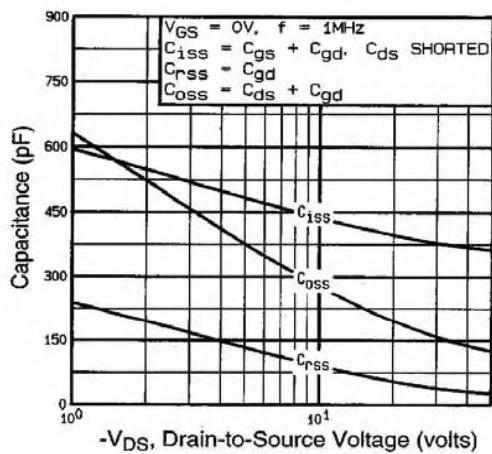


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage

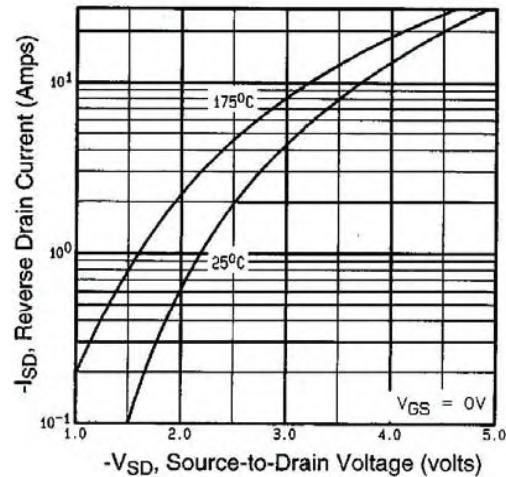


Fig. 7 - Typical Source-Drain Diode Forward Voltage

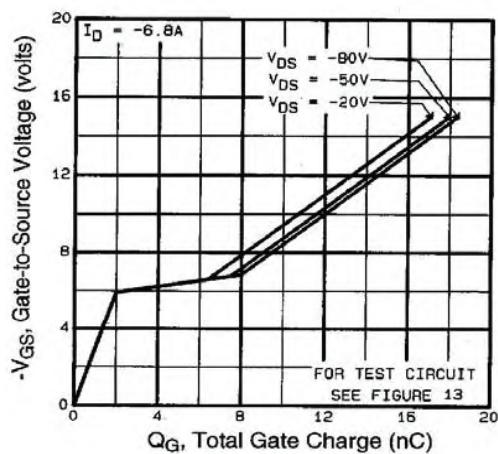


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

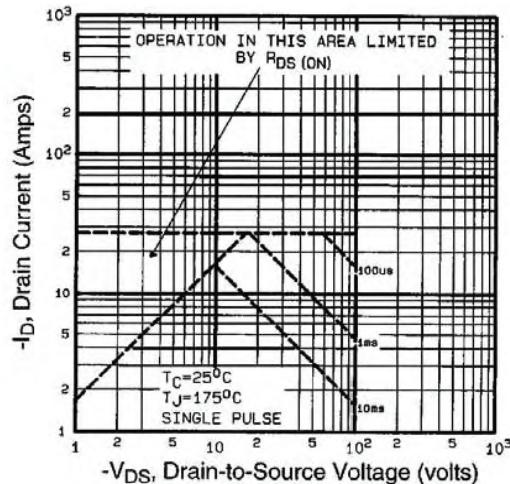


Fig. 8 - Maximum Safe Operating Area

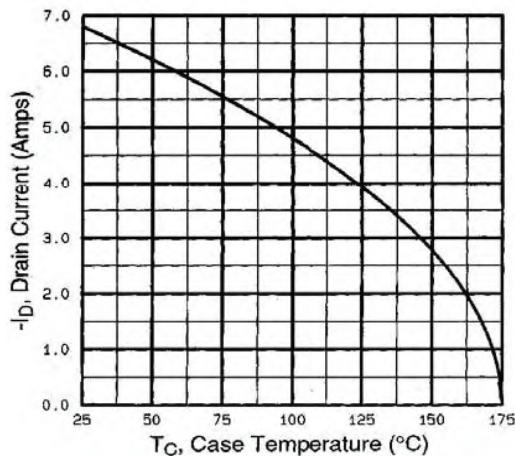


Fig. 9 - Maximum Drain Current vs. Case Temperature

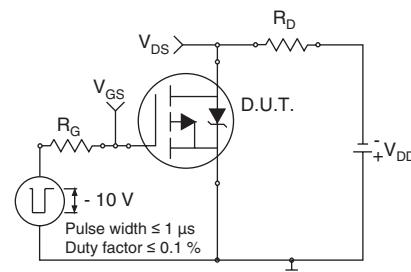


Fig. 10a - Switching Time Test Circuit

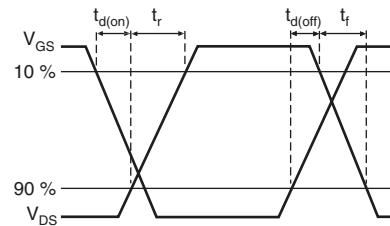


Fig. 10b - Switching Time Waveforms

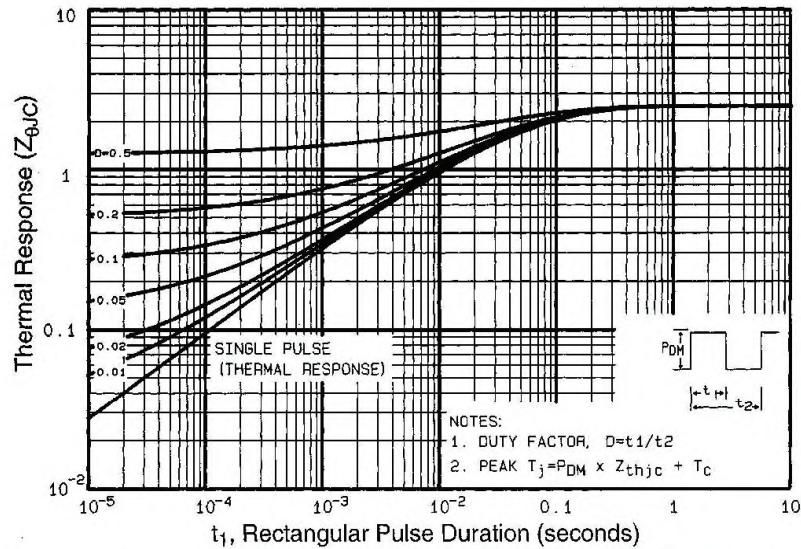


Fig. 11 - Maximum Effective Transient Thermal Impedance, Junction-to-Case

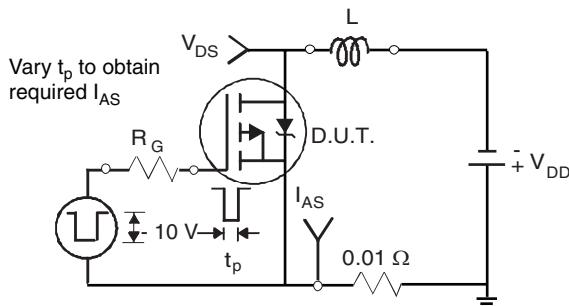


Fig. 12a - Unclamped Inductive Test Circuit

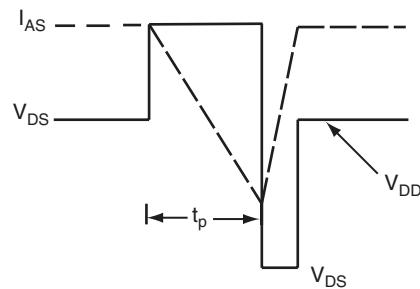


Fig. 12b - Unclamped Inductive Waveforms

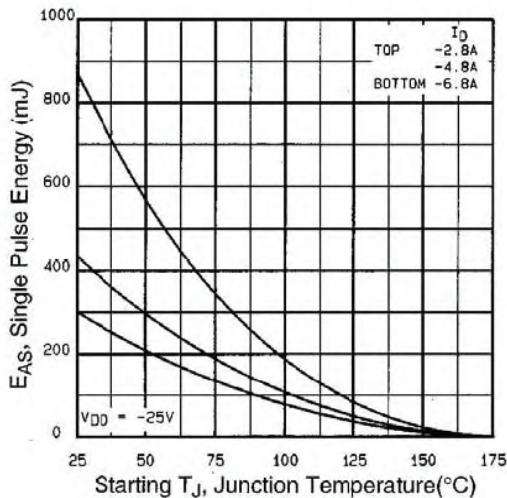


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

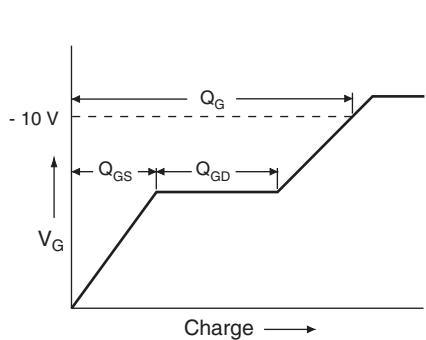


Fig. 13a - Basic Gate Charge Waveform

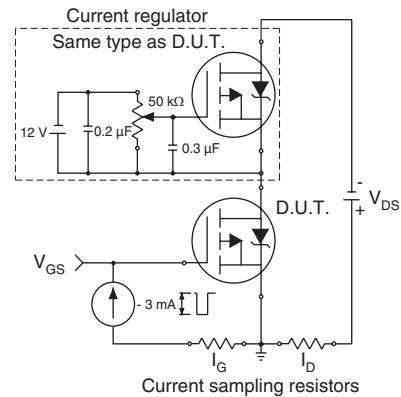
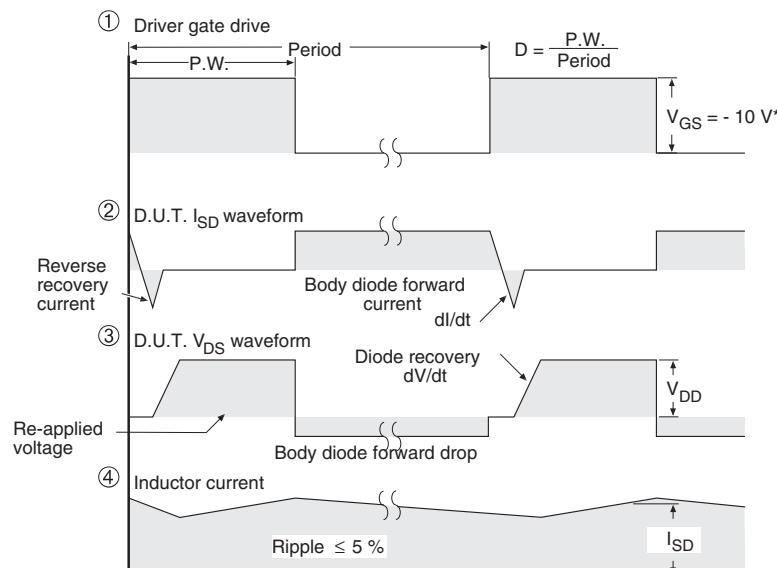
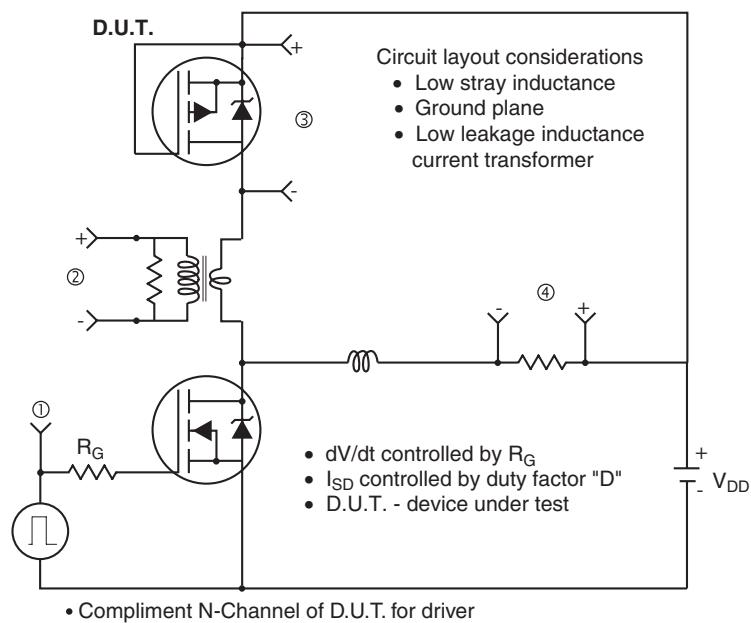


Fig. 13b - Gate Charge Test Circuit

### Peak Diode Recovery dV/dt Test Circuit



\*  $V_{GS} = -5 \text{ V}$  for logic level and  $-3 \text{ V}$  drive devices

**Fig. 14 - For P-Channel**

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